

FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 2003-0930.00/US	Serial No: 10/719,047 Not Assigned
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: Micron Technology, Inc.	
		Filing Date: November 20, 2003	Group: Not Assigned

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	
MP	AA 6,297,152	10/2001	Itoh et al.	438	649	
MP	AB 6,451,644	09/2002	Yu	438	230	
MP	AC 6,365,507	04/2002	Hu	438	627	
MP	AD 6,486,060	11/2002	Hermes et al.	438	649	
	AE					
	AF					
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	AK					

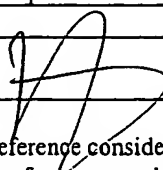
FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes	No
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	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>

Initial

OTHER ART (including author, title, date, pertinent pages, etc.)

MP	AO		Copending Application: "Conductive Transistor Structure for a Semiconductor Device and Method for Forming Same", Serial number 10/418,412, Docket Number 2002-1377.00, Filed April 16, 2003.
	AP		
	AQ		
	AR		

Examiner: 	Date Considered: 4/05
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.



Sheet: 1 of: 1

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		Filing Date: November 20, 2003	Group: 2811

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	
MP	AA 6,589,884	07/08/2003	Torek	438	755	
MP	AB 6,221,762	04/24/2001	Byun et al.	438	643	
MP	AC 6,075,274	06/13/2000	Wu et al.	257	413	
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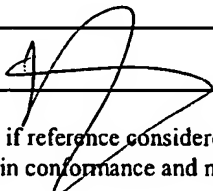
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	AM					<input type="checkbox"/>	<input type="checkbox"/>
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